

25-45GHz Driver

GaAs Monolithic Microwave IC in bare die

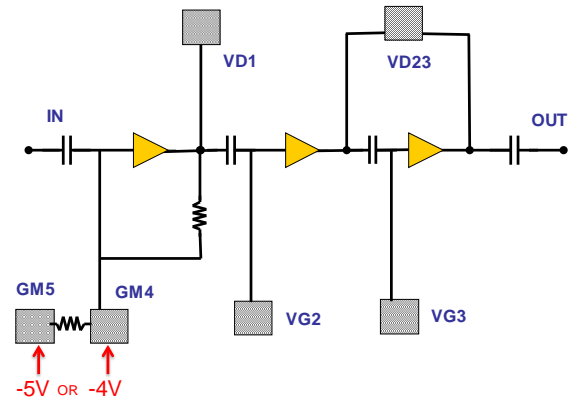
Description

The CHA3409-98F is a 3 stage monolithic Medium Power Amplifier, which produces 23dB linear gain and 19dBm output power. It includes a self-biasing on the first stage, which reduces the impact of temperature and technology variations.

It is well suited for a wide range of application from military to commercial communication systems and test instrumentation.

This product is manufactured with a pHEMT process, 0.15 μ m gate length, via holes through the substrate, air bridges and electron beam gate lithography.

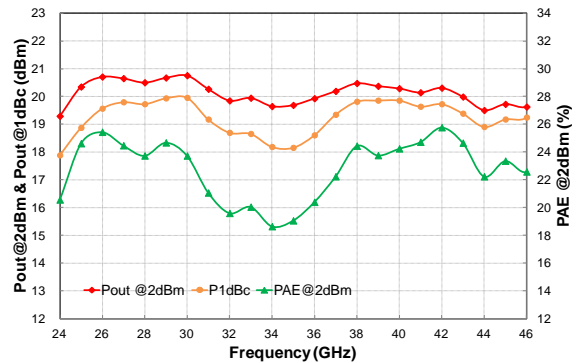
It is available in bare die with BCB protection layer.



Main Features

- Broadband performances: 25-45GHz
- 19dBm Pout at 1dB compression
- 23dB linear gain
- 19% of PAE @ 1dBc
- DC bias: Vd=4Volt @ Id=100mA
- Chip size 2x1.3x0.1 (mm)

Output power & PAE vs frequency



Main Electrical Characteristics

Tamb = +25°C, Vg_{stg1}=-4V, Vd=4V, Idq=100mA

Symbol	Parameter	Min	Typ	Max	Unit
Freq	Frequency range	25		45	GHz
Gain	Linear Gain		23		dB
P-1dB	Output Power @1dB comp.		19		dBm
Psat	Saturated output power		20		dBm
PAE	PAE @1dB comp.		19		%

Specifications (CW mode)

Tamb=+25°C, Vd=+4.0V

Symbol	Parameter	Min	Typ	Max	Unit
Fop	Operating frequency range	25		45	GHz
Gain	Linear Gain		23		dB
ΔG	Gain variation in temperature		± 0.03		dB/°C
P _{-1dB}	Output power @ 1dB gain compression		19		dBm
Psat	Saturated Output Power		20		dBm
PAE	PAE at saturation		19		%
NF	Noise figure		6.5		dB
RLin	Input Return Loss		-10		dB
RLout	Output Return Loss		-11		dB
Idq	Quiescent Drain current		100		mA
Vg	Gate voltage of 2 nd & 3 rd stage		-0.4		V
Vg _{stg1}	Gate voltage of the 1 st stage		-4		V

These values are representative of measurement in test fixture with a bonding wire of typically 0.25nH to 0.3nH.

Typical Bias Conditions

Tamb = +25°C

Symbol	Parameter	Values	Unit
GM4	GM4 OR GM5	-4	V
GM5	DC Gate voltage : 1 st stage	-5	V
G2 ⁽¹⁾	DC Gate voltage : 2 nd stage	-0.4	V
G3 ⁽¹⁾	DC Gate voltage : 3 rd stage	-0.4	V
D1	DC Drain voltage : 1 st stage	4	V
D23	DC Drain voltage : 2 nd & 3 rd stage	4	V

⁽¹⁾Corresponding to Idq=100mA

Biasing procedure

Device Power Up instructions:

1. Ground the device
2. Bias PA gate voltage at Vgs close to Vpinch-off (example: 1st stage Vgs \approx -7V and 2nd & 3rd stage Vgs \approx -1.5V)
3. Apply Vds quiescent bias voltage (Example: Vd = 4V)
4. Increase slowly 1st stage Vgs (GM4) up to -4V and 2nd & 3rd stage Vgs up to quiescent bias drain current Idq (100mA for total Idq current)
5. Apply RF input power

Device Power Down instructions:

1. Remove RF input power
2. Decrease MPA gate voltage down to Vgs -1.5V for the 2nd & 3rd stage Vgs and -7V for the first one
3. Decrease drain voltage down to 0V

Absolute Maximum Ratings ⁽¹⁾

Tamb = +25°C

Symbol	Parameter	Values	Unit
Vd	Drain bias voltage	8	V
Idq	Drain bias current	200	mA
Vg	Gate bias voltage of 2 nd & 3 rd stage	-2.5 to 0	V
Pin	Maximum peak input power overdrive	10	dBm
Tj	Junction temperature under ROR conditions	175	°C

⁽¹⁾ Operation of this device above anyone of these parameters may cause permanent damage.

Recommended Operating Range ⁽³⁾ ⁽⁴⁾

Tamb = +25°C

Symbol	Parameter	Values	Unit
Vd	Drain bias voltage	3 to 5	V
Idq	Drain bias current	100	mA
Vg	Gate bias voltage of 2 nd & 3 rd stage	-2.5 to 0	V
Vg _{stg1}	Gate voltage of the 1 st stage (GM4 or GM5)	-4 or -5	V
Pin	Maximum peak input power overdrive	10	dBm

⁽³⁾ Electrical performances are defined for specified test conditions

⁽⁴⁾ Electrical performances are not guaranteed over all recommended operating conditions

Temperature Range

Tamb	Operating temperature range	-40 to +85	°C
Tstg	Storage temperature range	-55 to +150	°C

Device thermal information

The device thermal performances below are based on UMS rules to evaluate the junction temperature.

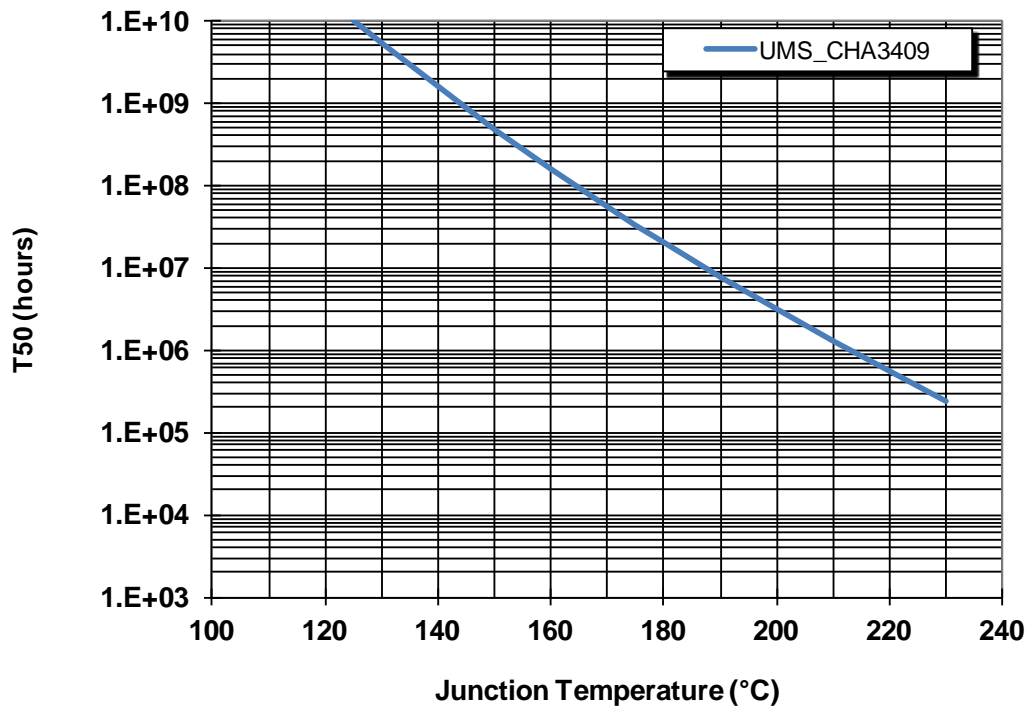
The temperature $T_{b_{chip}}$ is defined as the chip back side. The thermal resistance (R_{th_eq}) is given for the full circuit, and assumes CW operation mode in the table.

Thermal Resistance ⁽¹⁾	R_{th_eq}	$T_{b_{chip}} = 85^{\circ}\text{C}$, $V_d = 4\text{V}$, $V_{g_{stg1}} = -4\text{V}$, $I_{dq} = 100\text{mA}$	116	$^{\circ}\text{C}/\text{W}$
Junction Temperature	T_j	$P_{in} = -10\text{dBm}$, $P_{out} = 11\text{dBm}$, $P_{diss} = 390\text{mW}$	160	$^{\circ}\text{C}$

⁽¹⁾ Thermal resistance given from junction to back side of the chip

Thermal Resistance ⁽¹⁾	R_{th_eq}	$T_{b_{chip}} = 85^{\circ}\text{C}$, $V_d = 4\text{V}$, $V_{g_{stg1}} = -4\text{V}$, $I_{dq} = 100\text{mA}$	116	$^{\circ}\text{C}/\text{W}$
Junction Temperature	T_j	$P_{in} = 2\text{dBm}$, $P_{out} = 20\text{dBm}$, $P_{diss} = 355\text{mW}$	154	$^{\circ}\text{C}$

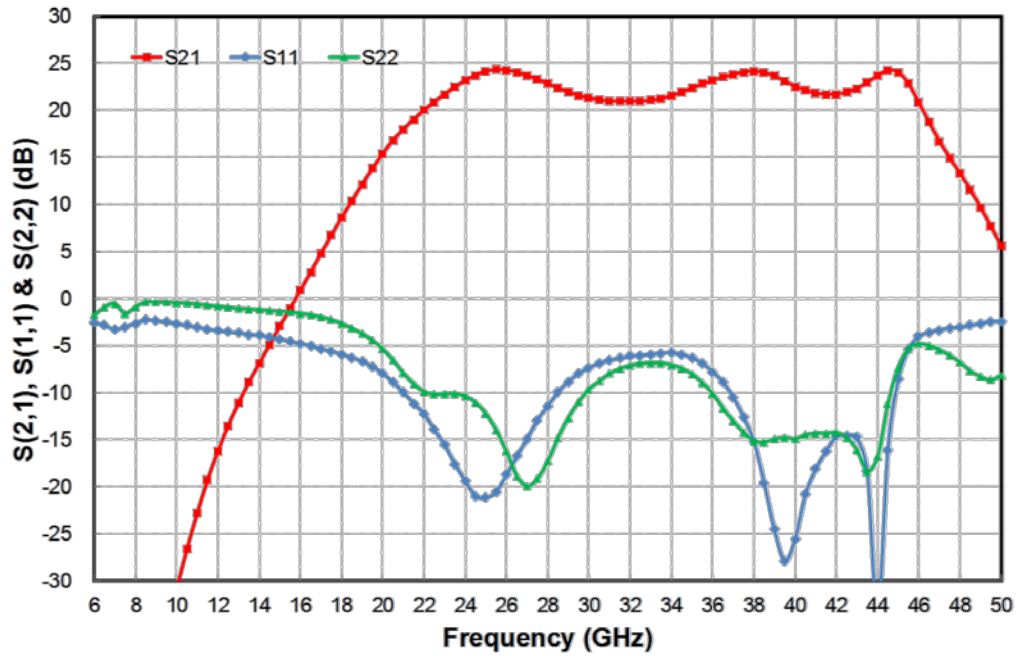
⁽¹⁾ Thermal resistance given from junction to back side of the chip. Thermal analysis is highly recommended, more details are available on request.



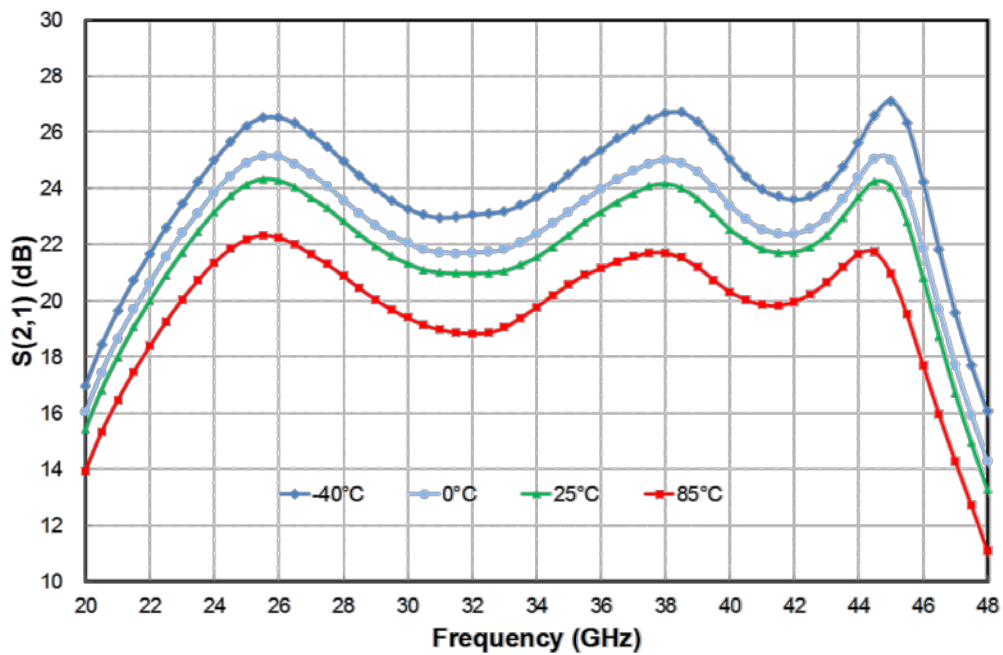
Typical On Board Sij Measurements

Tamb = +25°C, Vd = +4V, Vg1=-4V, other Vg fixed for Idq = 100mA@25°C
 Measurement performed on test board in the bonding wire access plans on the PCB.

Small Signal Gain (dB) and Input and Output Return Losses (dB) @25°C



Small Signal Gain (dB) versus Frequency (GHz) and temperature (°C)

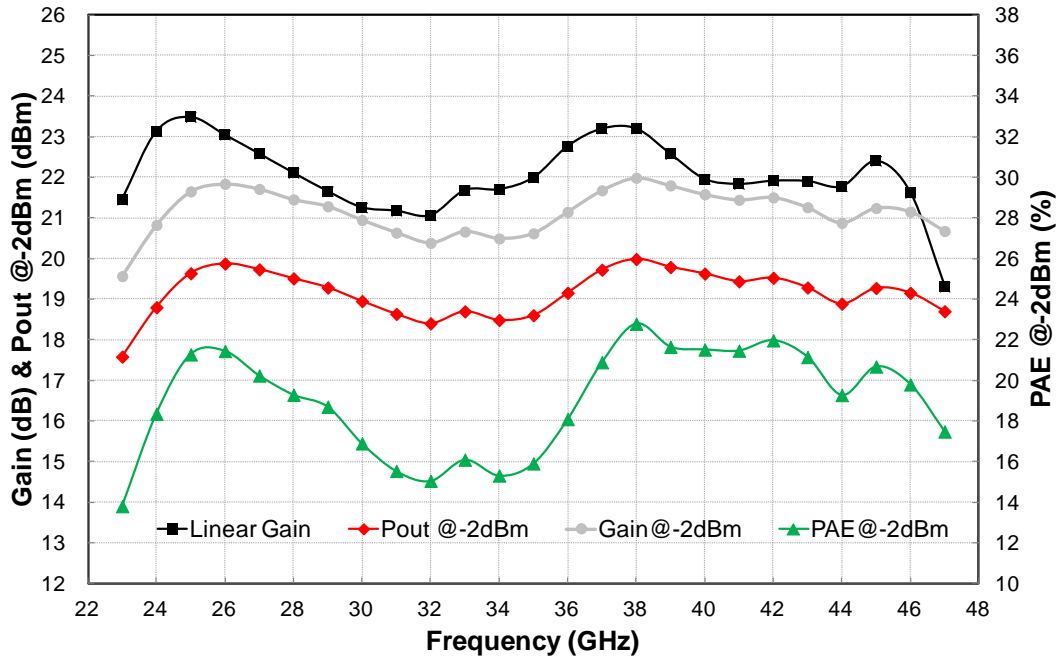


Typical On Board Measurements (CW)

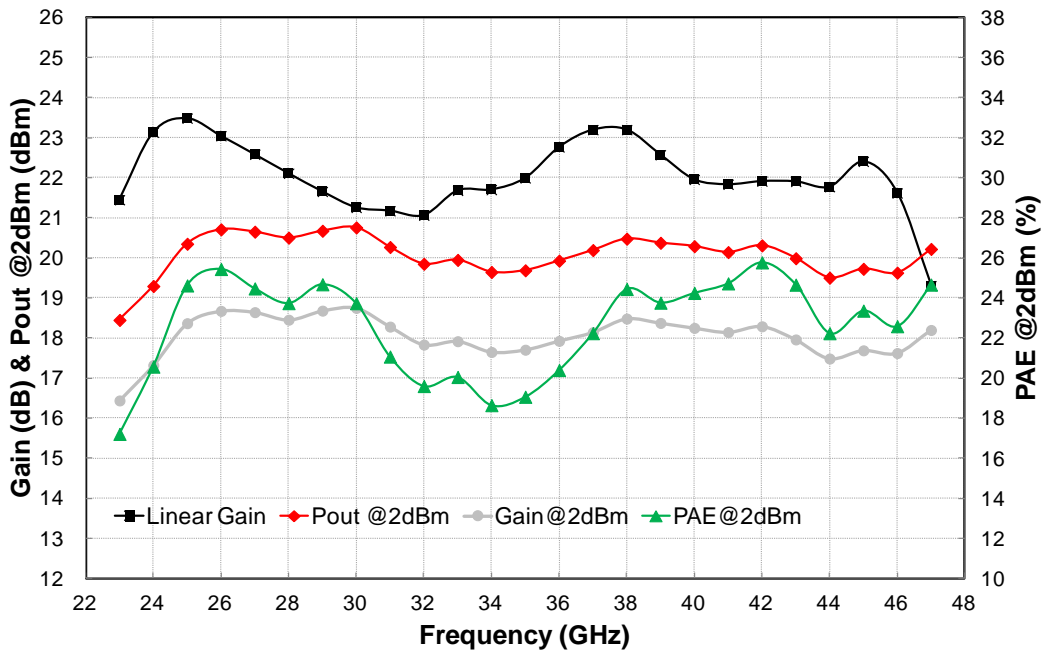
Tamb = +25°C, Vd = +4V, Vg1=-4V, other Vg fixed for Idq = 100mA@25°C

Measurement performed on test board in the bonding wire access plans on the PCB.

Linear Gain & Gain, Pout & PAE versus Frequency @Pin=-2dBm



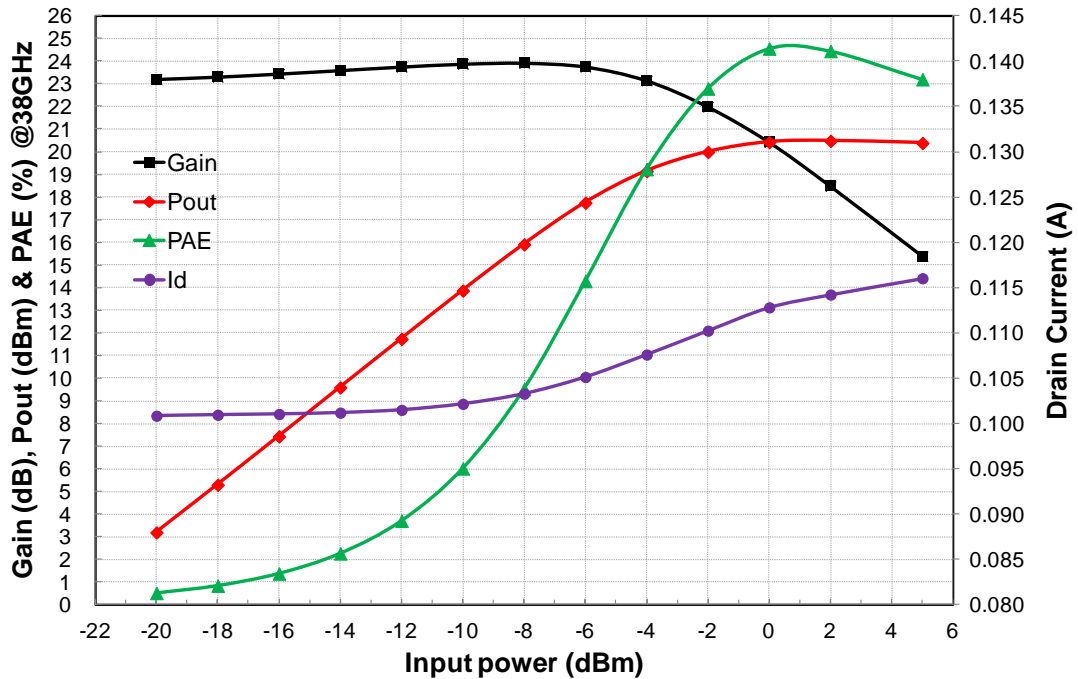
Linear Gain & Gain, Pout & PAE versus Frequency @Pin=2dBm



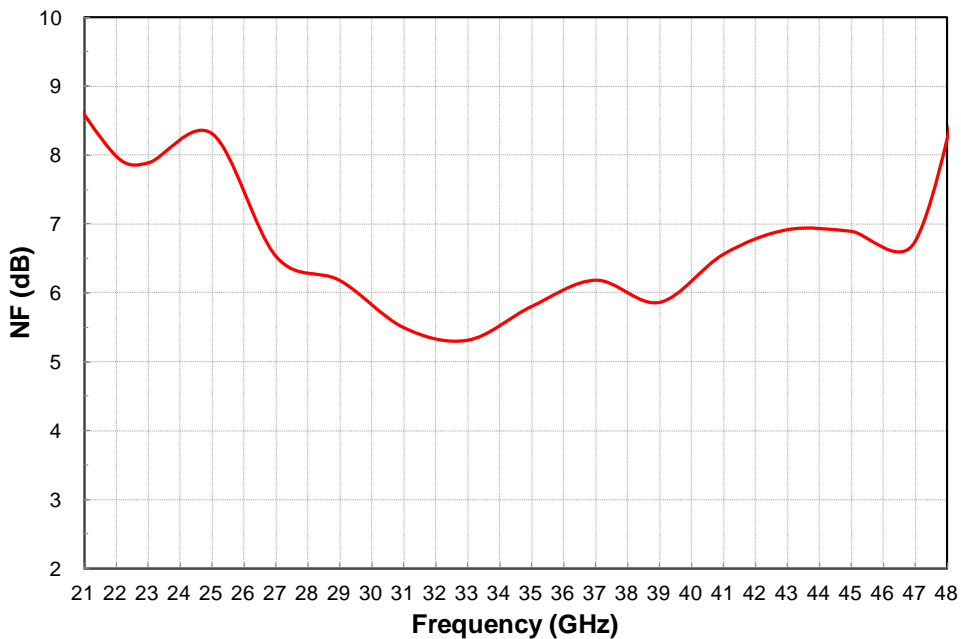
Typical On Board Measurements (CW)

Tamb = +25°C, Vd = +4V, Vg1=-4V, other Vg fixed for Idq = 100mA@25°C
 Measurement performed on test board in the bonding wire access plans on the PCB.

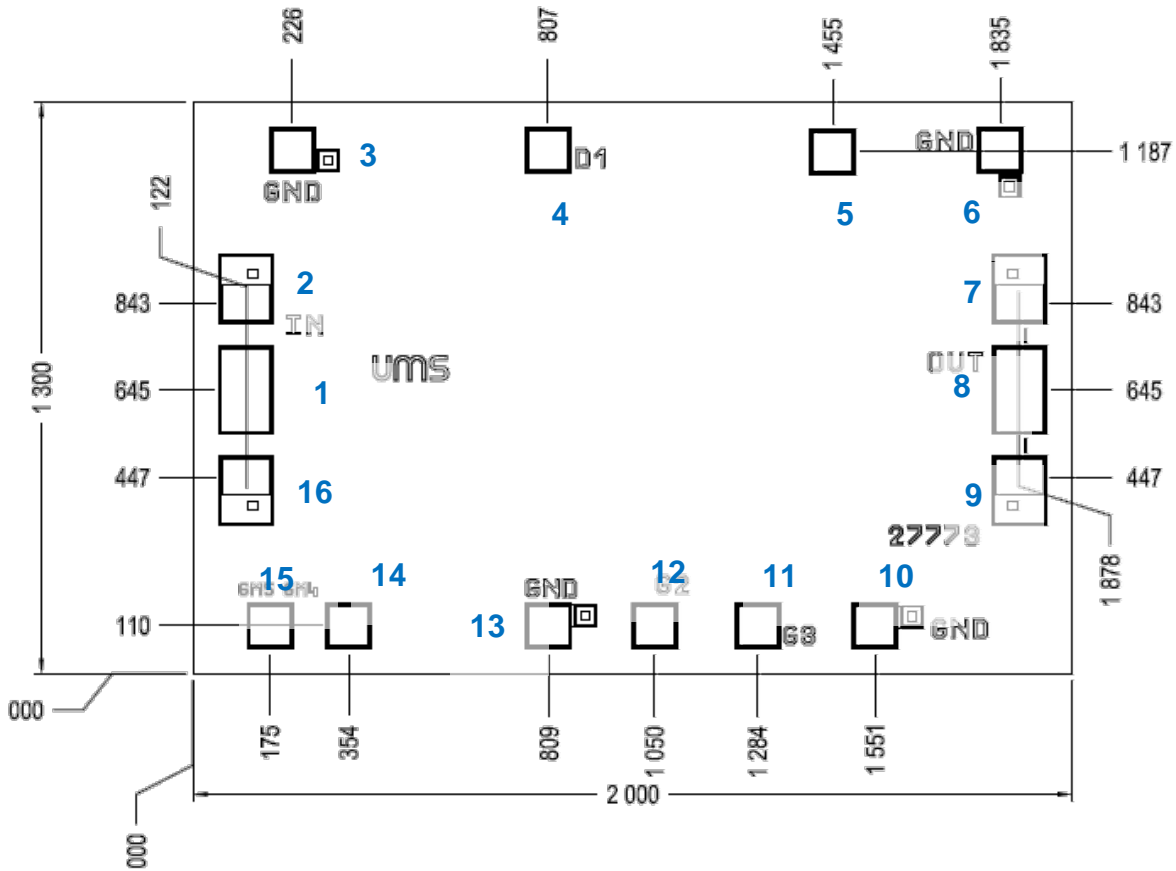
Gain, Pout, PAE & Id versus Pin @Freq=38GHz



Noise Figure @25°C versus Frequency



Mechanical data

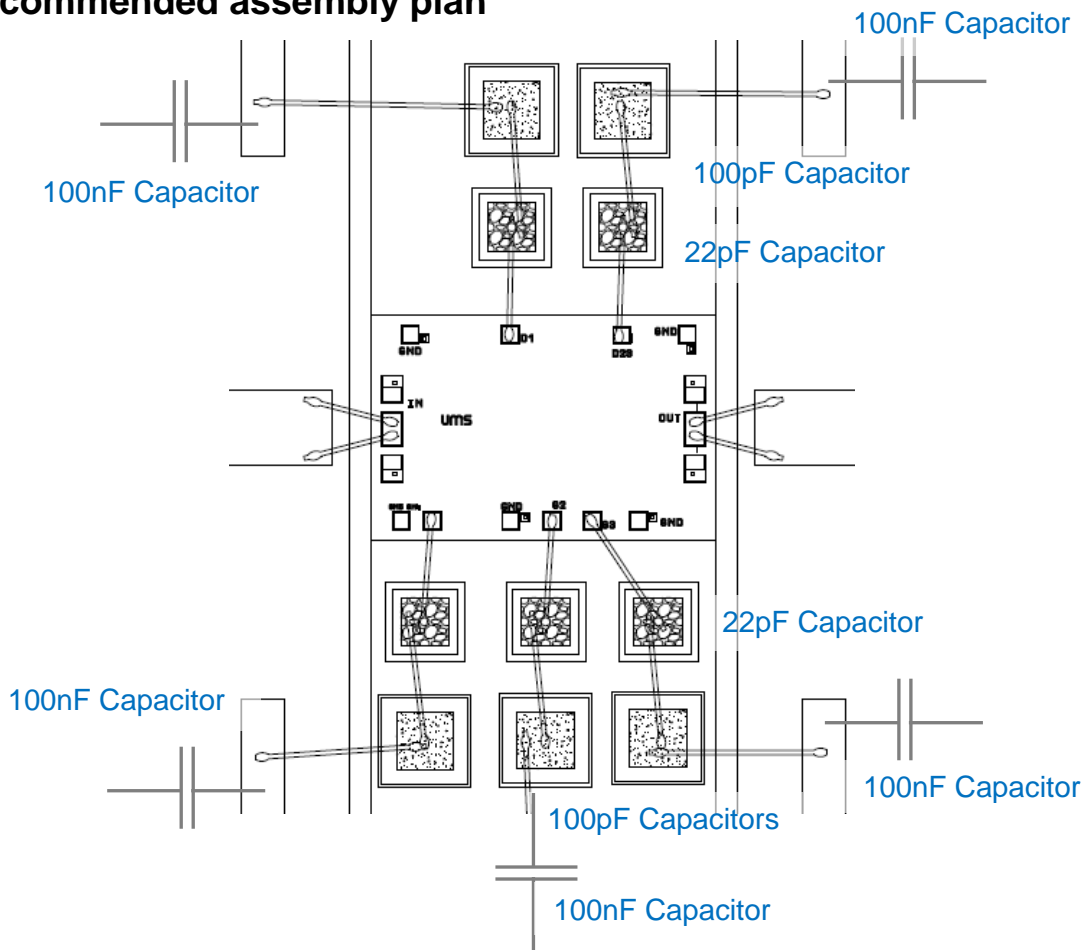


Tolerance chip size : +/-50µm
 Chip thickness: 70µm.
 All dimensions are in micrometers

PAD Number	Name	Description	Pad size (BCB Opening)
1	IN	Input RF port	186µm x 110µm
2, 7, 9, 16	GND	Ground cross to RF Pad	82µm x 108µm
3, 6, 10, 13	GND	Ground	90µm x 90µm
4	D1	DC Drain voltage 1 st stage	90µm x 90µm
5	D23	DC Drain voltage 2 nd & 3 rd stage	90µm x 90µm
8	OUT	Output RF port	186µm x 110µm
11	G3	DC Gate voltage 3 rd stage	90µm x 90µm
12	G2	DC Gate voltage 2 nd stage	90µm x 90µm
14	GM4 ⁽¹⁾	DC Gate voltage 1 st stage : If -4V	90µm x 90µm
15	GM5 ⁽¹⁾	DC Gate voltage 1 st stage : If -5V	90µm x 90µm

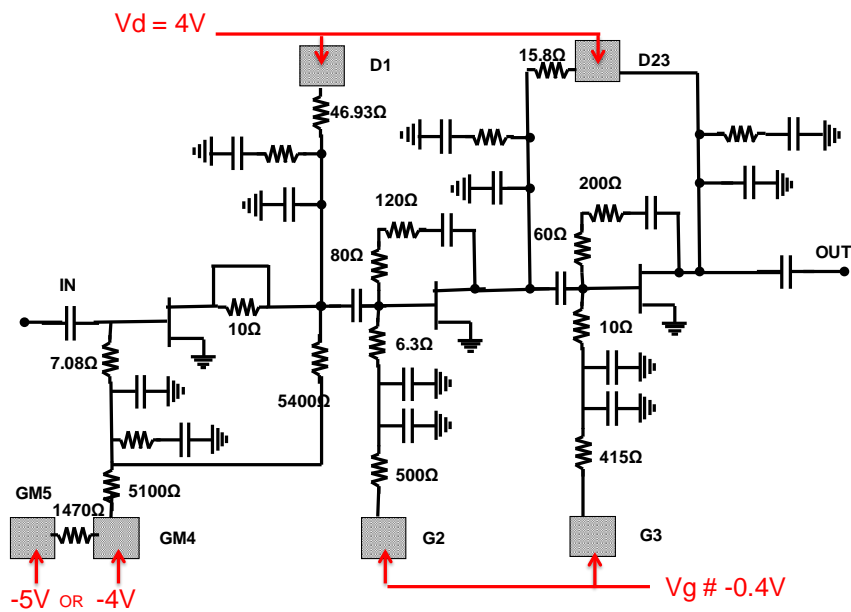
(1): Only 1 pad between GM4 and GM5 has to be connected, depend on external voltage using (-4V or -5V). There is only a resistor between GM4 and GM5 Pads.

Recommended assembly plan



Note: Supply feed should be bypassed. 25 μ m diameter gold wire is to be preferred.

DC Schematic



Recommended ESD management

Refer to the application note AN0020 available at <https://www.ums-rf.com> for ESD sensitivity and handling recommendations for the UMS products.

Recommended environmental management

UMS products are compliant with the regulation in particular with the directives RoHS N°2011/65 and REACH N°1907/2006. More environmental data are available in the application note AN0019 also available at <https://www.ums-rf.com>.

Ordering Information

Chip form:

CHA3409-98F/00

Information furnished is believed to be accurate and reliable. However **United Monolithic Semiconductors S.A.S.** assumes no responsibility for the consequences of use of such information nor for any infringement of patents or other rights of third parties which may result from its use. No license is granted by implication or otherwise under any patent or patent rights of **United Monolithic Semiconductors S.A.S.**. Specifications mentioned in this publication are subject to change without notice. This publication supersedes and replaces all information previously supplied. **United Monolithic Semiconductors S.A.S.** products are not authorised for use as critical components in life support devices or systems without express written approval from **United Monolithic Semiconductors S.A.S.**